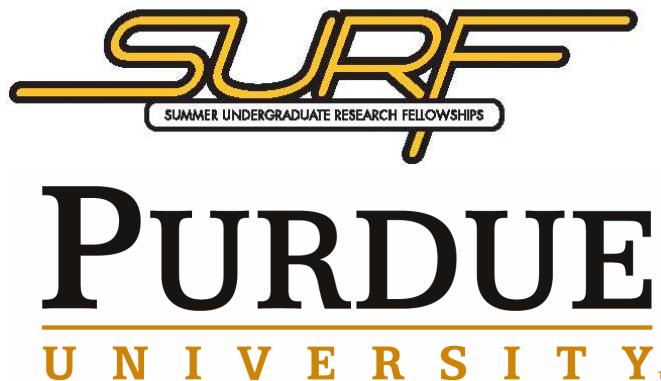




## *Network for Computational Nanotechnology (NCN)*

Purdue, Norfolk State, Northwestern, MIT, Molecular Foundry, UC Berkeley, Univ. of Illinois, UTEP



## nanoFET: Upgrading to NEMO5



Semiconductor  
Research  
Corporation



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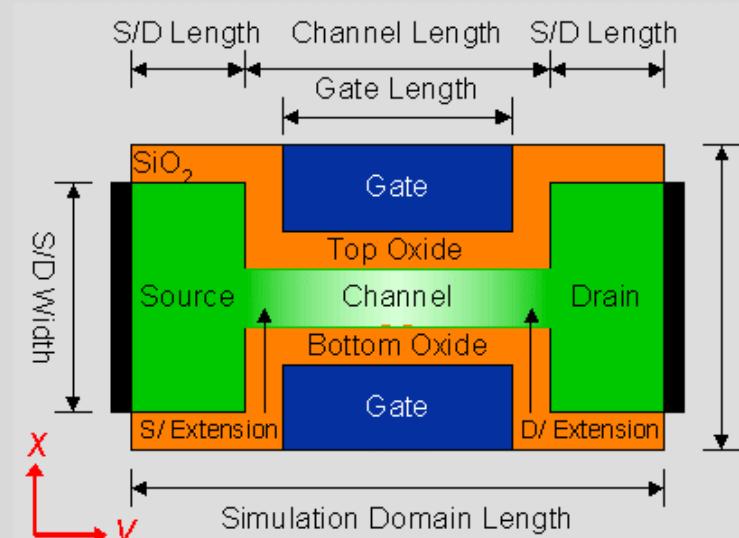
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- Introducing nanoFET
- Software & Simulations
- Working with Inputs
- Current Status
- Future Work
- Questions

# Introducing nanoFET

- Overview
  - Simulates ballistic transport in 2D, double-gated MOSFET devices
  - Four phases of inputs
- Objective
  - Upgrade tool using newly developed software

1 Device Settings → 2 Material Settings → 3 Bias Settings → 4 Simulator Settings



Dimensions    Mesh/Grid    Doping

Simulation Domain Length:	29nm
Simulation Domain Width:	24nm
Source/Drain Length:	6nm
Source/Drain Width:	3nm
Channel Length:	17nm

[Material Settings >](#)

- Dimensions

- Simulation domain
- Source/Drain
- Channel
- Gate
- Oxide

- Mesh & Grid

- No. of grid
- Grid Size along channel

- Doping

- Impurity atoms per cm<sup>3</sup>

Dimensions | Mesh/Grid | Doping |

Simulation Domain Length: **29nm**

Simulation Domain Width: **24nm**

Source/Drain Length: **6nm**

Source/Drain Width: **3nm**

Channel Length: **17nm**

Channel Width/Thickness: **3nm**

Gate Length: **9nm**

Top Oxide Thickness: **1nm**

Bottom Oxide Thickness: **1nm**

Dimensions | Mesh/Grid | Doping |

No. of Grid (nx) in Top Oxide: **5**

No. of Grid (nx) in Channel: **15**

No. of Grid (nx) in Bottom Oxide: **5**

Grid Size Along Channel (deltaY): **0.3nm**

Dimensions | Mesh/Grid | Doping |

Source/Drain Doping (/cm<sup>3</sup>): **2.e20**

Source/Drain Extension Doping Type: **Gaussian**

Gaussian Parameter, g (db/nm): **1**

S/D Extension Abrupt Doping (/cm<sup>3</sup>): **2.e20**

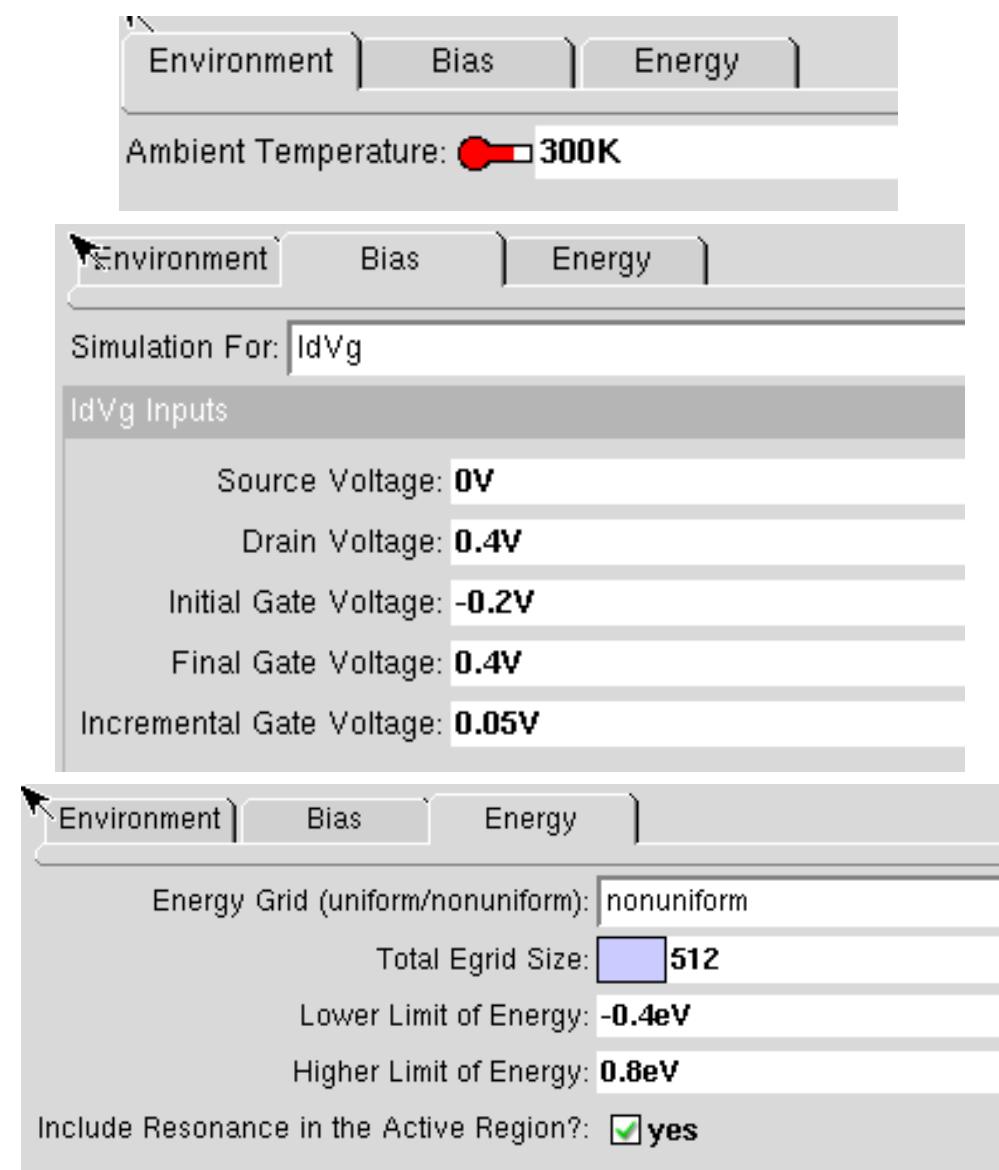
Gate Polysilicon Doping (/cm<sup>3</sup>): **2.e20**

Channel/Body Doping (/cm<sup>3</sup>): **-0.e20**

- Silicon
  - Effective Masses
  - Dielectric Constant
  - Band Gap
  - Affinity
- Gate
  - Metal or n-Polysilicon
- Gate Oxide
  - SiO<sub>2</sub> or Other Oxide
  - Must specify Other Oxide Parameters

Silicon	Gate	Gate Oxide
Electron Longitudinal Effective Mass: <b>0.98</b>		
Electron Transverse Effective Mass: <b>0.19</b>		
Hole Effective Mass in Silicon: <b>0.49</b>		
Silicon Dielectric Constant: <b>11.7</b>		
Silicon Band Gap: <b>1.12eV</b>		
Silicon	Gate	Gate Oxide
Silicon Affinity: <b>4.05eV</b>		
Gate Type: <b>Metal</b>		
Top Metal Gate Workfunction: <b>4.188eV</b>		
Bottom Metal Gate Workfunction: <b>4.188eV</b>		
Silicon	Gate	Gate Oxide
Gate Oxide Type: <b>SiO<sub>2</sub></b>		
Electron Effective Mass in Top Oxide: <b>0.5</b>		
Hole Effective Mass in Top Oxide: <b>0.5</b>		
Top Oxide Dielectric Constant: <b>3.9</b>		
Top Oxide Band Gap: <b>8.8eV</b>		
Top Oxide Affinity: <b>0.95eV</b>		
Electron Effective Mass in Bottom Oxide: <b>0.5</b>		
Hole Isotropic Mass in Bottom Oxide: <b>0.5</b>		
Bottom Oxide Dielectric Constant: <b>3.9</b>		
Band Gap in Bottom Oxide: <b>8.8eV</b>		
Bottom Oxide Affinity: <b>0.95eV</b>		

- Environment
  - Temperature of environment around device
- Bias (applied voltage)
  - $IdVg$  (gate controlled),  $IdVd$  (drain controlled), or single bias
  - Incremental gate voltage determines step size between bias points
  - Gate voltage controls both top and bottom gate
- Energy
  - Uniform or nonuniform grid



The screenshot shows the 'Bias Settings' interface with three tabs at the top: Environment, Bias (selected), and Energy.

**Ambient Temperature:** 300K

**Simulation For:**  $IdVg$

**IdVg Inputs**

- Source Voltage: 0V
- Drain Voltage: 0.4V
- Initial Gate Voltage: -0.2V
- Final Gate Voltage: 0.4V
- Incremental Gate Voltage: 0.05V

**Energy Grid (uniform/nonuniform):** nonuniform

**Total Egrid Size:** 512

**Lower Limit of Energy:** -0.4eV

**Higher Limit of Energy:** 0.8eV

**Include Resonance in the Active Region?**:  yes

- Simulator Options
  - Full Simulation or Flat Potential
- Simulator Parameters
  - Sets up simulation time

Simulation Options    Simulator Params

Simulation Mode: **FullSimulation**

Solve Poisson?:  **yes**

No. of Poisson Iterations:  **10**

Include Electron Mass Anisotropy?:  **yes**

Calculate LessThan Green's Function?:  **yes**

Calculate GreaterThan Green's Function?:  **yes**

Do a Backward Recursion?:  **yes**

Depth for 1D-Plot Along Length: **1nm**

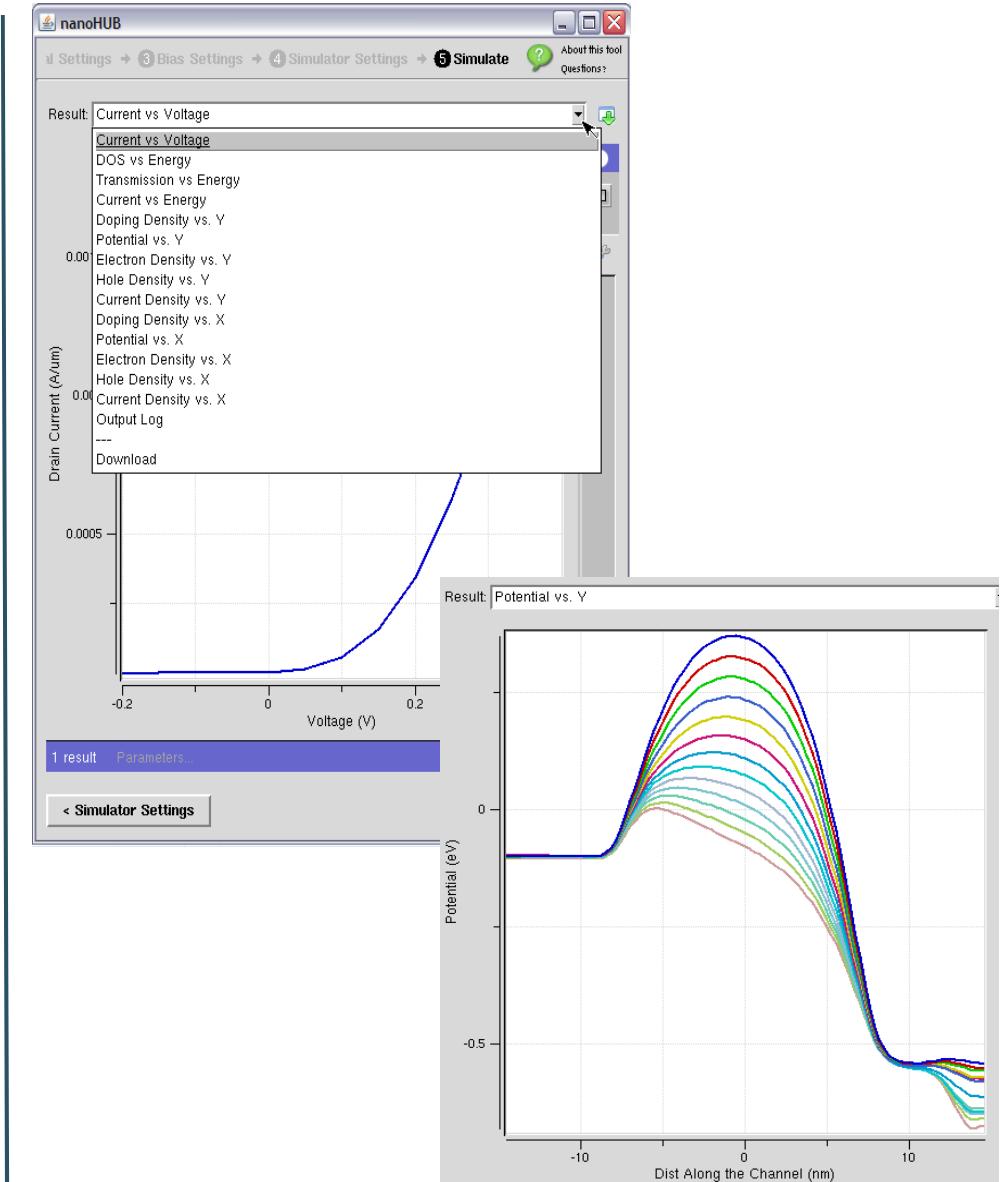
Length for 1-D Plot Along Depth: **14.5nm**

Simulation Options    Simulator Params

Estimated Run Time: **02:00:00**

Format is hh:mm:ss (hh = hour, mm = minutes, ss)

- 14 plots
  - Current vs. Voltage
  - Density Of States vs. Energy
  - Current vs. Energy
  - Doping Density vs. Y, vs. X
  - Potential vs. Y, vs. X
  - Electron Density vs. Y, vs. X
  - Hole Density vs. Y, vs. X
  - Current Density vs. Y, vs. X
- Output Log
- Plots are downloadable



### Rappture

- Rapid Application Infrastructure
- Can be used with C, C++, Fortran, MATLAB, Octave, Perl, Python, and Tcl.
- Creates graphical user interface (GUI)
- Two files:
  - XML tool description
  - Launcher file

### NEMO5

- NanoElectronics MOdeling Tools
- Klimeck research group at Purdue
- Two input files:
  - Input deck
  - Material database file

# Parts of a Simulation: Rappture

## tool.xml

- Extensible markup language
- Input/output description
- Lists characteristics of each parameter

```

- <number id="ChannelLength">
- <about>
  <label>Channel Length</label>
  <description>Channel Length is considered to be the
    total distance in between the Source and Drain
    regions (Channel Length = 2*(S/D Extension
    Length) + Gate Length).</description>
  <color>green</color>
</about>
<units>nm</units>
<min>1nm</min>
<max>100nm</max>
<default>17.0nm</default>
</number>
- <number id="ChannelWidth">
- <about>
  <label>Channel Width/Thickness</label>
  <color>green</color>

```

## Launcher file

- User chooses language
- Three parts
  - Inputs from GUI
  - Algorithm
  - Results back to GUI

```

// Get the current paths (equivalent to UNIX pwd)
char input_dir[1000];
char *cwd=getcwd(NULL,0);
sprintf(input_dir,"%s", cwd);

char output_dir[1000];
sprintf(output_dir,".");

printf("Input directory: %s\n", input_dir);
printf("Output directory: %s\n", output_dir);

/*#####
   READ INPUT FROM lib & STORE IN VARIABLES
#####*/

```

## Parts of a Simulation: NEMO5

### Input Deck

- Specifies material/device and simulation information
- Contains three sections
  - Structure, Solvers, Global

```
Structure
{
    Material
    {
        tag = channel

        name = Si
        crystal_structure = simplecubic
        regions = (2)
        Lattice:a_lattice = 0.300

        Bands:BandEdge:mstar_c_dos = 0.980
    }

    Material
    {
        tag = lead

        name = Si
    }
}
```

### Material Database

- Specifies material parameters
- File provided by NEMO5 developers

```
# Si from Si.mat substrate file

group Si {
    unit_cell = 0.27155;
    type      = "IV";
    group Lattice {
        variables   = "Tkel";
        a_lattice   = 0.54310;
        #a_lattice  = 0.543; #Mathieu
        epsilon_dc = 11.9;
        c11         = 1.675;
        c12         = 0.650;
        c44         = 0.801;
        c_elastic   = cp_3tol(c11,c12,c44);
        bdp         = -2.1;
        ddp         = -4.8;

        element     = Si;
        Si_mass     = 28.0855;
        Si_mass_ref = "NIST periodic table";

        #strain_alpha = 48.5;
        #strain_beta  = 13.8;
        #strain_ref   = "Martin, PRB 1 (1970)";
    }
}
```

## Working with Inputs

- Used same tool.xml
- Launcher file
  - Completed reading inputs from GUI

```
//Phase: Device Settings, Group: Dimensions
    rpGetString(lib,"input.phase(DevPhase).group(param).number(Ly).current", &data);
    Ly = rpConvertDbl(data, "nm", &err);
    if (err) {printf("Error while retrieving Simulation Domain Length."); exit(1);}
```

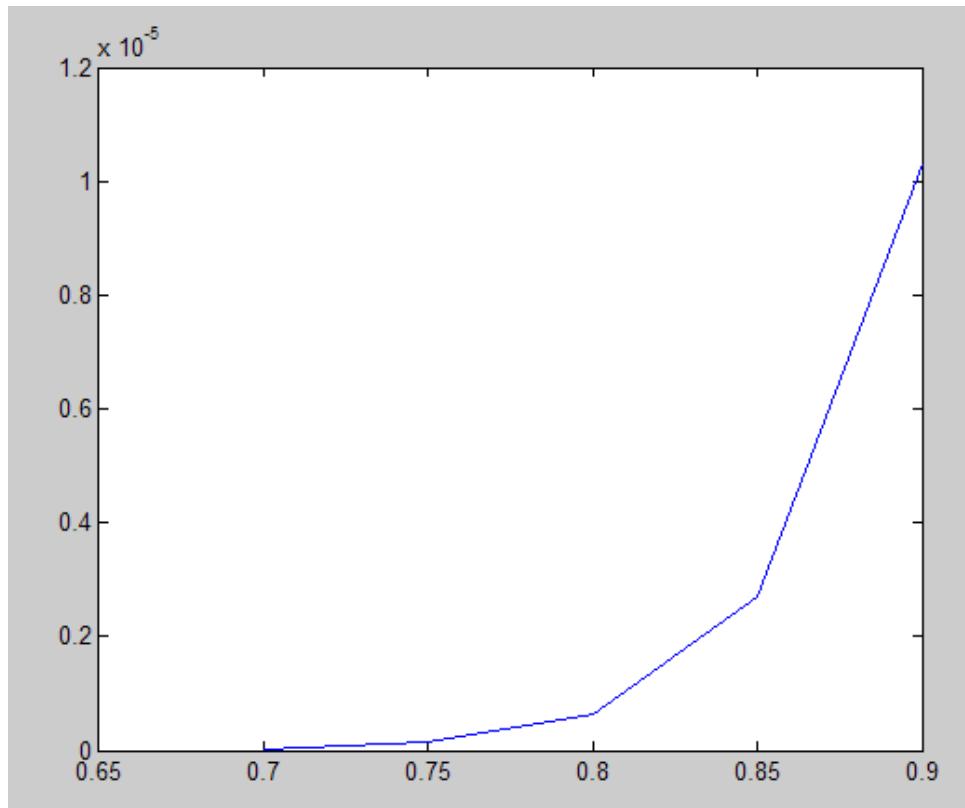
- Working on printing input deck
- Working with developers
- Currently, 50% of inputs completed

```
//STRUCTURE

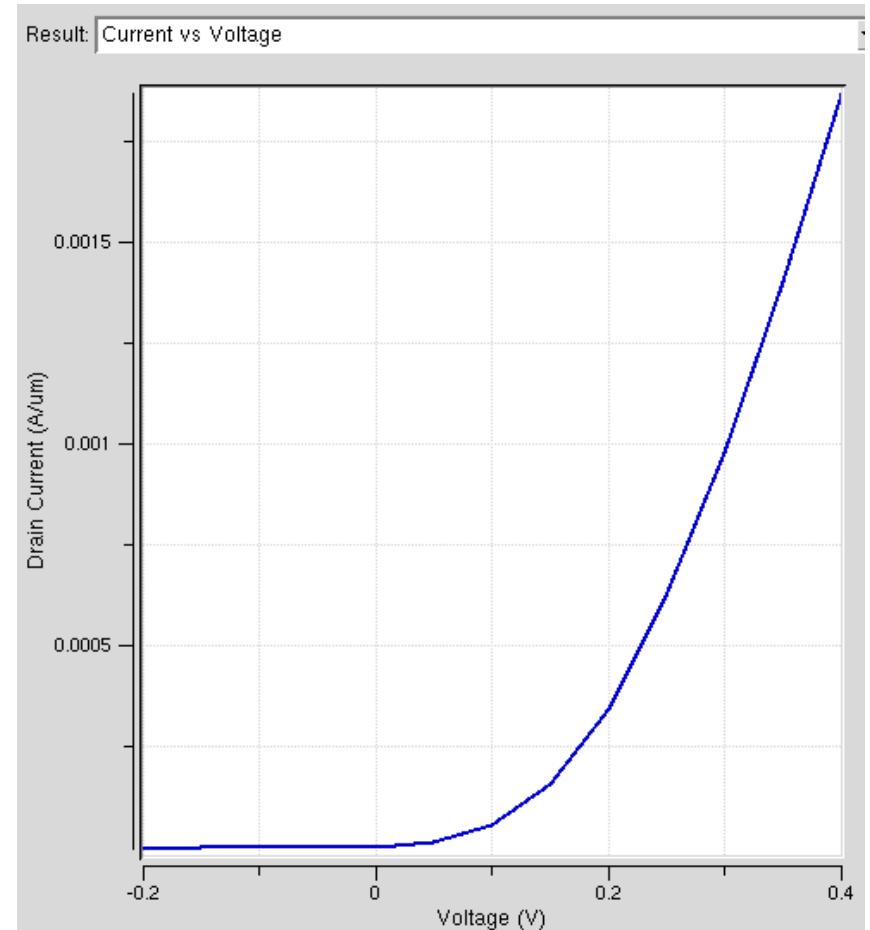
//Structure/Material/Channel
fprintf(fpideck,"Structure\n{\n\tMaterial\n\t{\n");
    fprintf(fpideck," \ttag = channel\n\t\tname = Si\n\t
\tcrystal_structure = simplecubic\n\t\tregions = (2)"); //sections that
won't change (tag, name, crystal structure, and regions)
    fprintf(fpideck," \t\tlattice:a_lattice = %.3f\n\t} ",GridSizeY);
//lattice
```

## Current Status

### Current Output

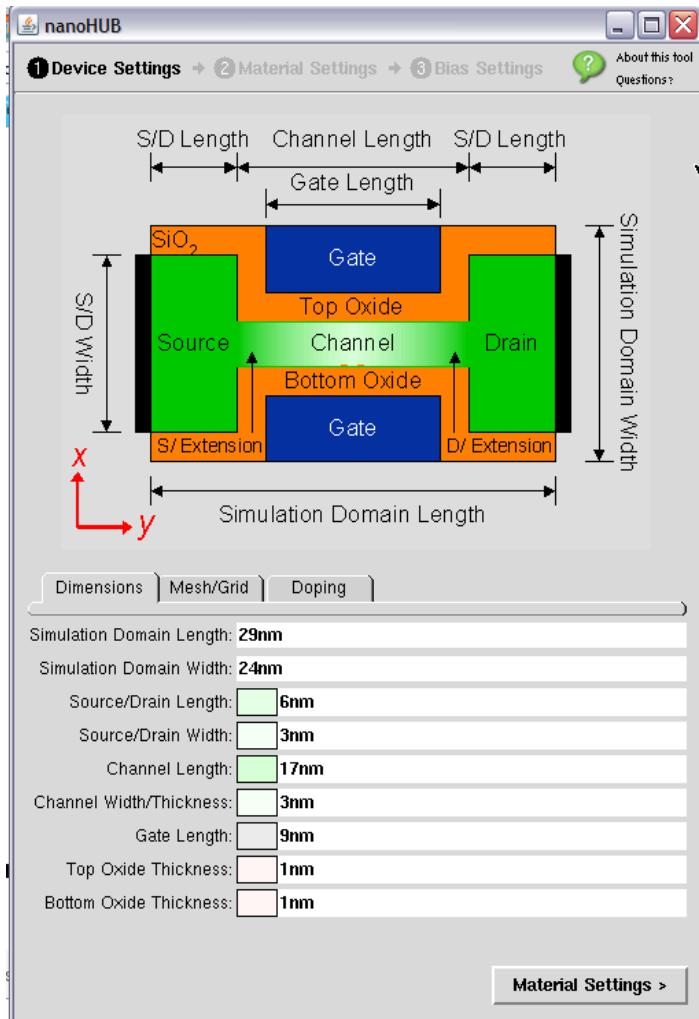


### Desired Output



## Future Work

- To finish tool
  - Incorporate or remove remaining inputs
  - Run NEMO5 simulation
  - Resulting data must be read back into the launcher file
  - Graphs created and sent to GUI
- Testing of tool
- Create user guide
- Launch on nanoHUB



# Questions?